


Laboratoire  
d'Informatique  
de Robotique  
et de Microélectronique  
de Montpellier

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## « Embedded Test Challenges around SiP technologies »

Pascal Nouet

SiPeX Workshop – Verbania, may 29, 2008



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## Outline

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- Context, know-how and skills of the team
- Embedded Test by the example
  - ✓ MIDISPPi
    - Funded by the French Research Agency in 2006
    - Started March 2007
  - ✓ R3MEMS
    - Funded by the French Research Agency in 2007
    - Started January 2008

# Context

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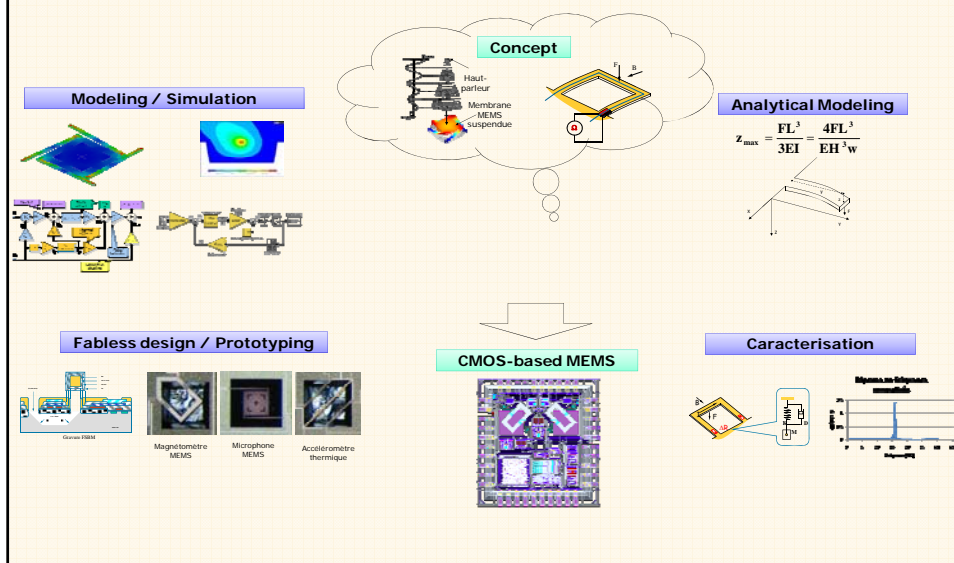
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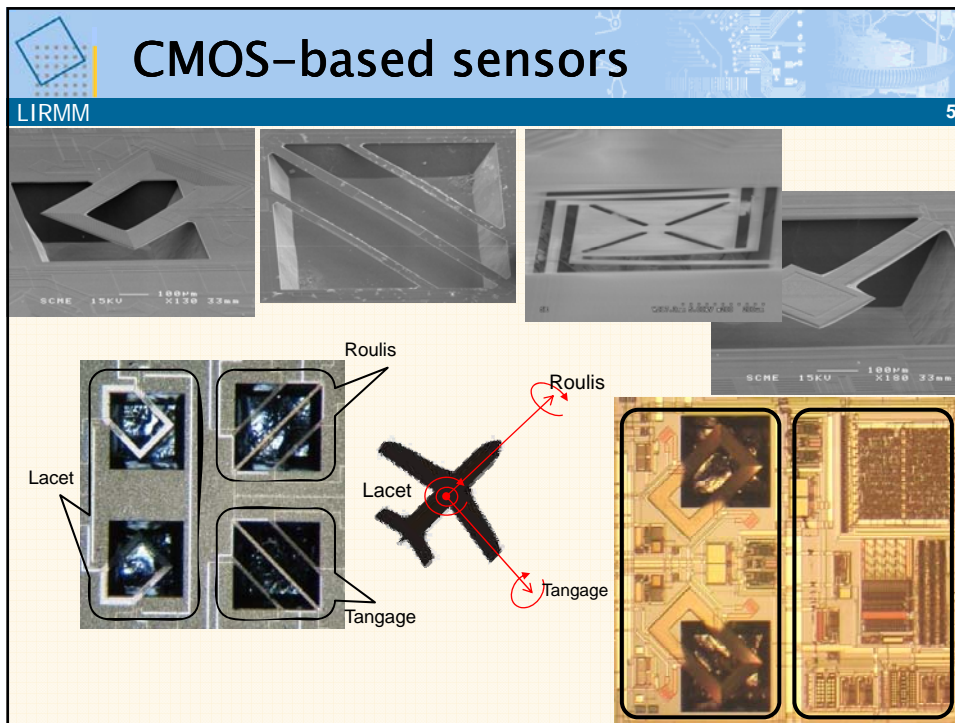
- MEMS rather than MEMs
- Balanced development time between technology, modeling, design, test, ...
- Stable technology is needed → CMOS process
  - ✓ EM Device is low performance, portable, low-cost
  - ✓ High NRE for an up-to-date CMOS process (MEMS devices + ASIC)
  - ✓ Non-planar CMOS process is preferred

# Fabless design flow

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# MIDISPPi Project

## « Smart Cap for Smart Sensors »

ANR Project – 2006  
N. Pous, F. Maily, P. Nouet, L. Latorre

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MEMS Reliability Workshop – Toulouse, may 29–30, 2008

## The MIDISPPi Project

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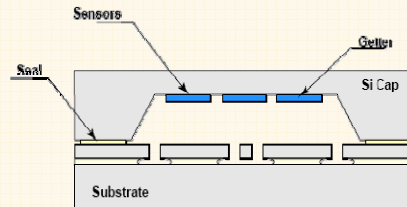
### Academic Partners:

- ✓ IEF (Orsay)
- ✓ IMS (Bordeaux)
- ✓ LIRMM (Montpellier)



### Industrial Partners:

- ✓ NXP



- Design and realization of a smart packaging : Integrating microsensors in the cap for the monitoring of the package internal environment.
- Various test devices will be integrated: Temperature, Pressure and Humidity sensor.
- The ultimate goal is to obtain a «zero-defect» final test method.
- Calibration & compensation functions

## Context: The PICS substrate

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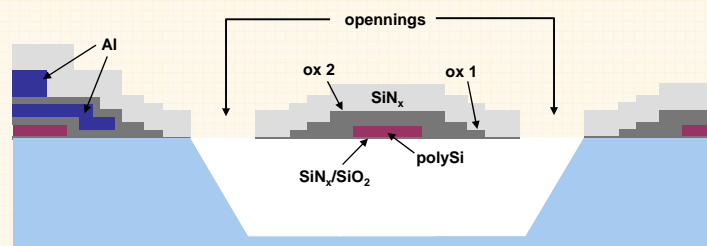
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### PICS

- ✓ 25–50nm of  $\text{SiN}_x/\text{SiO}_2$
- ✓ One polysilicon layer
- ✓ 2 interconnect levels (Al)
- ✓ 2 oxides ( $\text{SiO}_2$ ) layers + 1 passivation ( $\text{SiN}_x$ ) layer

### MEMS compatibility

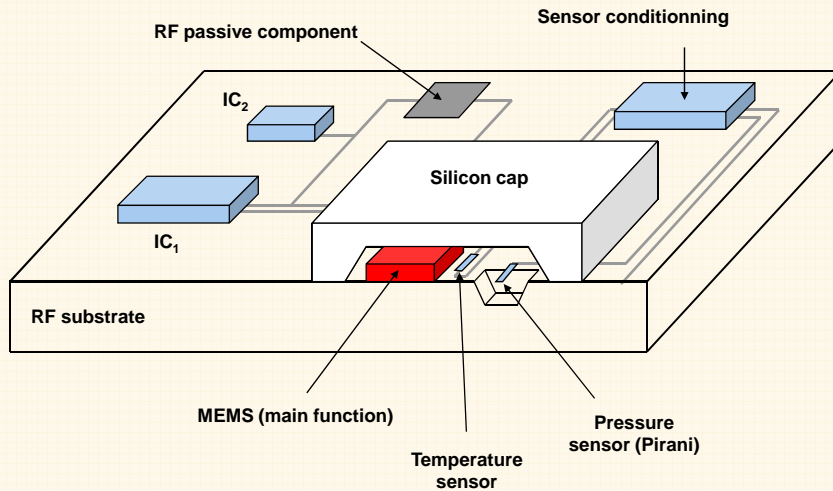
- ✓ TMAH /FSBM : fabrication of suspended structures
- ✓ PolySi : Thermal and mechanical sensitivity



## Context: The PICS substrate

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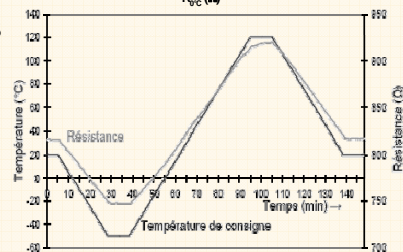
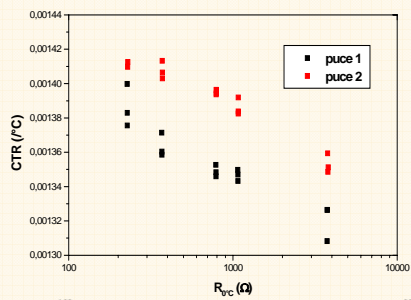
Extra-hardware must be highly reliable and low cost....

## Temperature sensor

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- Use of PICS polysilicon
- Measure of thermal coefficient between 20 and 90°C (LIRMM)
  - ✓ Good linearity ( $r > 0.999$ )
  - ✓  $0,13\%/^{\circ}\text{C} < \text{CTR} < 0.14\%/^{\circ}\text{C}$
- Confirmed by IMS measurements between  $-50$  et  $120^{\circ}\text{C}$



# Pirani Gauge Working Principles

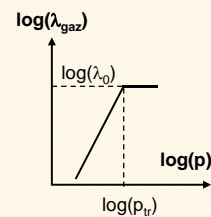
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- ✓ Use of a suspended resistor as a heater (FSBM)
- ✓ Thermal equilibrium:
  - Heat conduction into materials to the substrate
  - Radiation losses (usually negligible)
  - Heat conduction or natural convection into surrounding gas (related to the pressure)

- ✓ Gas thermal conductivity:
  - Negligible for  $p \ll p_{tr}$
  - Constant ( $\lambda_0$ ) for  $p \gg p_{tr}$

$$\lambda_{gaz}(p) = \lambda_0 \frac{p}{p + p_{tr}}$$



- ✓ 2 techniques for pressure measurement
  - Temperature measurement at constant power
  - Power measurement at constant temperature

# Transition pressure

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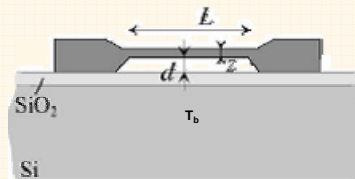
- Related to molecule free minimal path ( $l$ ) :

$$l = \frac{kT}{\sqrt{2} p \pi a^2} \quad \text{pour } N_2, \pi a^2 = 0,43 \text{ nm}^2 \Rightarrow L \# 150 \text{ nm @ } 20^\circ\text{C}$$

- $p_{tr}$  as a function of molecules speed and air gap:

$$p_{tr} = \lambda_0 \frac{w T_b}{(w + z) d \bar{v}}$$

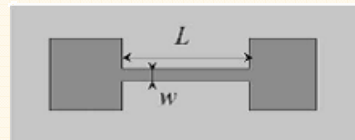
R. Puers et al, Sens. Actuators A 97-98 (2002), 280-214



- $p_{tr}$  as a function of air gap and  $l$

$$p_{tr} = \frac{\bar{v} C_v}{2 RT} l p \frac{d}{d + 2l \left( \frac{2}{\alpha_E} - 1 \right)}$$

M. Kimura et al, Microelectronics Journal 38 (2007), 171-176



# Thermal Equilibrium

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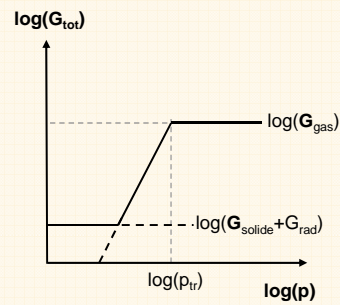
$$G_{tot} = G_{solide} + G_{rad} + G_{gas} \frac{p}{p + p_{tr}}$$

✓ Under vacuum ( $p \ll p_{tr}$ )

$$\Rightarrow G_{solide} + G_{rad}$$

✓ At  $p \gg p_{tr}$

$$\Rightarrow G_{tot} \text{ puis } G_{gas}$$



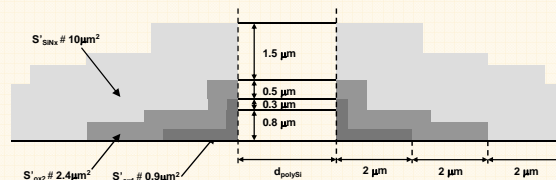
# Prototyping

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## Prototype features

- ✓  $R_{0^{\circ}C} = 390\Omega$ ,  $CTR = 0,138\%/^{\circ}C$
- ✓ Length =  $1020\mu m$ , width (polysilicium):  $d_{polySi} = 25\mu m$
- ✓ Cross-section area :  $S_{tot} \sim 104\mu m^2$
- ✓ Beam exchange surface :  $S_{tot} \sim 78500\mu m^2$



## Temperature regulation ( $T_c = 316^{\circ}C$ )

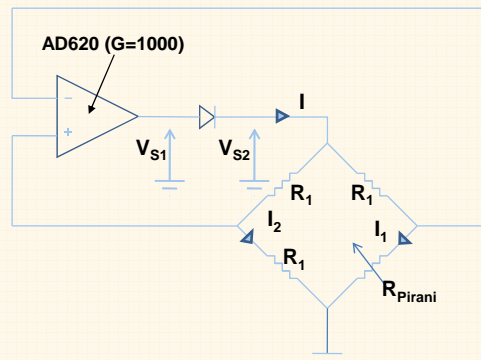
- ✓  $R_{Pirani} @ T_c$   $R(T) = R_{0^{\circ}C} (1 + CTR \cdot T_c) = 560\Omega$

# Conditionning Circuit

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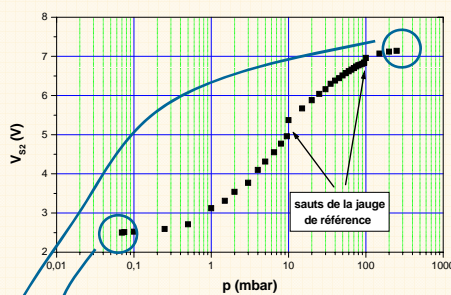
- $R_1 = 560\Omega$
- Two stable states :
  - ✓ All potentials are zero (impossible due to noises and offsets)
  - ✓  $I_1$  large enough to heat the Pirani resistor, giving  $R_{Pirani} \neq R_1$  and  $T_{Pirani} \neq T_c$  et  $V^+ \neq V^-$



# Experimental results

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$$V^+ - V^- \approx \frac{V_{S2}(R_1 - R_{Pirani})}{4R_1}$$

$$V_{S1} = G(V^+ - V^-) \approx V_{S2} + 0.7$$

$$\Rightarrow T_{Pirani} = \frac{R_1 - R_{0^\circ C}}{CTR \cdot R_{0^\circ C}} - \frac{(V_{S2} + 0.7) \cdot 4R_1}{G \cdot V_{S2} \cdot CTR \cdot R_{0^\circ C}}$$

$$T_{Pirani} = 316^\circ C - \varepsilon$$

$$V_{S2} = 2.5V \Rightarrow \varepsilon = 5.3^\circ C \Rightarrow G_{solide} + G_{rad} \approx \frac{P_j}{T_{Pirani} - 20^\circ C} = \frac{2.8 \cdot 10^{-3}}{290.5} = 9.65 \cdot 10^{-6} W / K$$

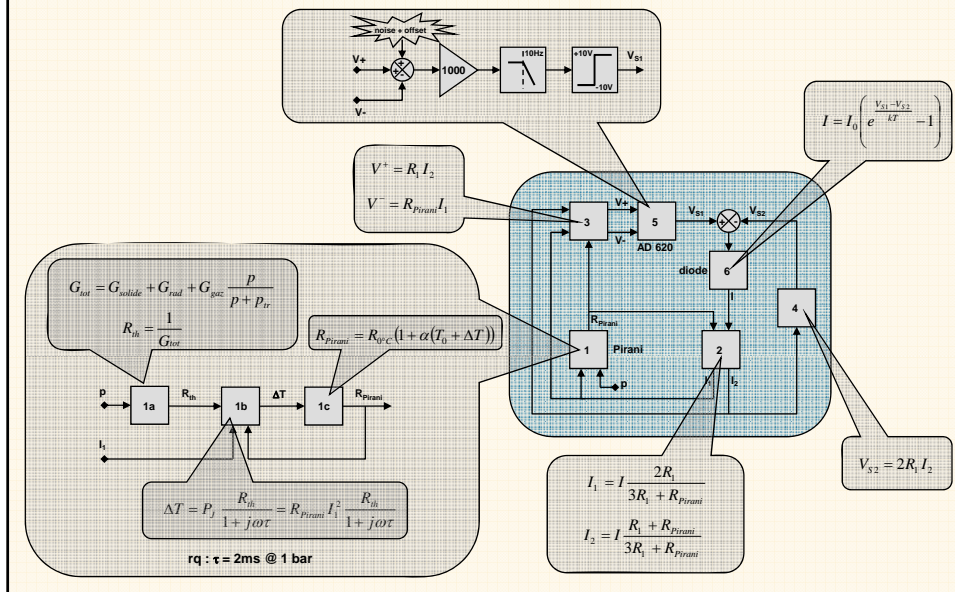
$$V_{S2} = 7.14V \Rightarrow \varepsilon = 4.6^\circ C \Rightarrow G_{tot} \approx \frac{P_j}{T_{Pirani} - 20^\circ C} = \frac{2.29 \cdot 10^{-2}}{291.3} = 7.85 \cdot 10^{-5} W / K$$

$$G_{air} \approx 6.88 \cdot 10^{-5} W / K \Rightarrow h_{air} \approx 876 W \cdot m^{-2} \cdot K^{-1}$$

# Modeling (Matlab/Simulink)

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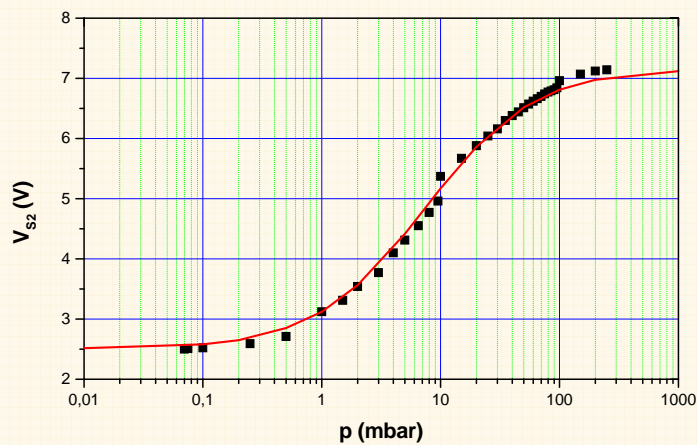
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# Simulation vs Measurements

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Fits @  $p_{tr} = 12 \text{ mbar}$

# Porous Silicon Humidity Sensor

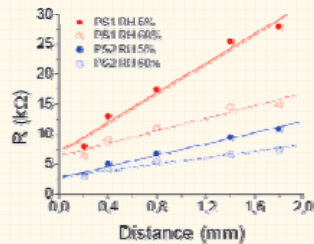
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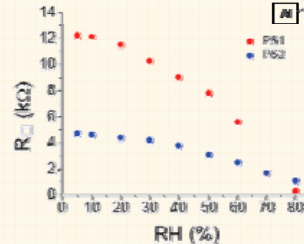


## ➤ Resistive Humidity Sensor

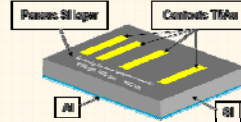
- First results:



Variation of resistance of PS1 and PS2 versus distance between contacts



Sheet resistance  $R_{sh}$  versus RH from 5 to 80%



At moisture levels smaller than 70% relative humidity (RH), resistance increases with specific surface.

The sample with the higher specific surface (PS1) is about 10 times more resistive than the other (PS2).

Reference: W. Ludwicki, O. Gasiot, C. Pellat, E. Dufour-Gergare, F. Verjus, Influence on moisture sensor performances, and characterization of different specific area porous silicon layers, IEEE Sensors, 2007 conference, 2007

# Conclusion

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- Approach strengths
  - ✓ Use of PICS substrate
  - ✓ Simple conditioning circuits
  - ✓ Modeling in good agreement with experiment
- Integration of the conditioning circuits
- Thermal conductivity of materials need to be studied
  - ✓ Under vacuum, using various geometries
  - ✓ Support from FEM (coventor)
- Air conductivity
  - ✓  $876 \text{ W}\cdot\text{m}^{-2}\cdot\text{K}^{-1}$
  - ✓ Higher than reported
  - ✓ Requires a precise knowledge of prototype geometry (e.g. air gap)


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# R3MEMS Project

## « MEMS-based reflect array antenna »

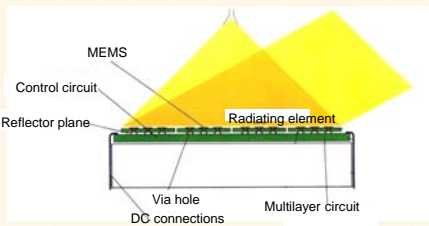
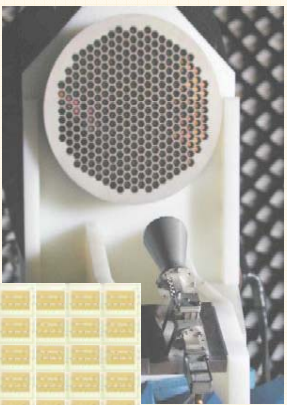
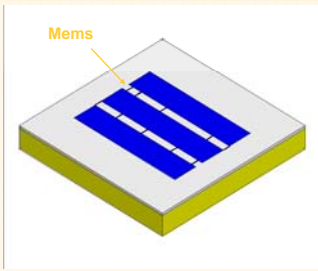
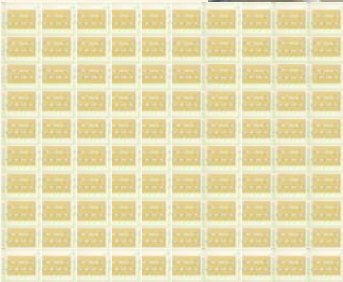
ANR Project - 2007  
N. Dumas, F. Mailly, P. Nouet, L. Latorre



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# Context

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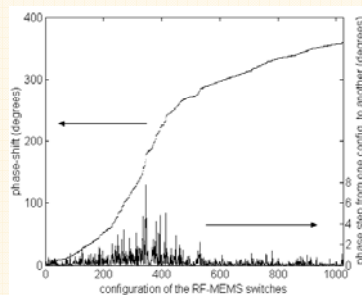





## Main challenges

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- Assembling - Packaging
- ...
- Control → 10,000 electrostatic actuators
- Robustness → solved by redundancy



## Embedded Test

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- No extra cost  
→ use of the same infrastructure than for control
- Verify the actuation → Con/Coff
- Memory-like
- Scan-chain like

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# Thank you !!!



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